## Notice of References Cited Application/Control No. 10/606,623 Examiner Devona E. Faulk Applicant(s)/Patent Under Reexamination EID ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,757,927	05-1998	Gerzon et al.	381/20
*	В	US-7,035,413	04-2006	Waller et al.	381/17
*	С	US-6,349,285	02-2002	Liu et al.	704/500
*	D	US-2004/0114771	06-2004	Vaughan et al.	381/086
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	F	US-			
	G	US-			
	Ξ	US-			
	ı	US-			
	7	US-			
	Κ	US-			
	L	US-			<u> </u>
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## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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